

**Search Notes**

Application/Control No.

10/717,033

Examiner

Christopher M. Keehan

Applicant(s)/Patent under  
Reexamination

ELAU ET AL.

Art Unit

1712

**SEARCHED**

Class	Subclass	Date	Examiner
528	32		
	10		
	125		
	127		
	170		
	205		
	220		
	397		
	401		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
same as	above	4/14/2005	CMK

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	4/14/2005	CMK
Inventor name search		
10/005584, 09/619237, and STN structure searched therewith		